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Application/Control No.	Applicant(s)/Patent un Reexamination	der
10/658,823	DEFREES, SHAWN	
Examiner	Art Unit	
Rin Shen	1657	

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Class	Subclass	Date	Examiner
NA	NA	1/16/2007	BS
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INT	INTERFERENCE SEARCHED		
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	DATE	EXMR
Brenda-see printout.	1/16/2007	BS
Priority document checked.	1/16/2007	BS
Inventor name searched.	1/16/2007	BS
SEQ search: NA.	1/16/2007	BS